## UNITED STATES PATENT AND TRADEMARK OFFICE

Re:

Application of:

Xavier VILANOVA et al.

Serial No.:

Not yet known

Filed:

Herewith

For:

ANALYZING SYSTEM FOR THE DETECTION OF REDUCING AND OXIDIZING GASES IN A

CARRIER GAS WITH A METAL-OXIDE-

SEMICONDUCTOR SENSOR ARRANGEMENT

## **INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 June 15, 2005

Dear Sir:

Pursuant to M.P.E.P. §609 and 37 C.F.R. §§1.56, 1.97-1.99, applicant submits herewith an information disclosure citation which lists references of which the applicant is aware. A copy of each of the references is also submitted herewith.

An English translation of DE 195 34 557 is not available at this time. It is respectfully submitted that the relevance of this reference can be readily understood by referring to the drawings of the patent provided.

This submission does not represent that a search has been made or that no better art exists. While the term "references" is used in citing the publications called to the examiner's attention herein, applicants do not make any admission that each or all of them are "prior art" references within the meaning of the statutory and case law.

JC20 Rec'd PCT/PTU 1 5 JUN 2005

Applicant reserves the right to contend, where appropriate, that a reference asserted against any claim of the present application is not prior art under the facts and the law.

Applicant also reserves the right to present appropriate arguments and/or evidence to establish patentability over the references, should one or more of the references be applied against the claims of the present application.

Applicant respectfully requests that the examiner independently determine those items which the examiner would consider the most pertinent of all the references cited herein.

Applicant respectfully requests that the references be considered and made of record.

This Information Disclosure Statement is being filed simultaneously with the filing of the application and therefore no fee is due. However, in the event that a fee is required, the Director is hereby authorized to charge any deficiency or credit any overpayment to Deposit Account No. 500518.

Respectfully submitted,

Reg. No. 42,507

Encls. PTO-1449

5 References

International Search Report

Steinberg & Raskin, P.C.

1140 Avenue of the Americas, 15th Floor

New York, NY 10036-5803

Telephone: (212) 768-3800

Facsimile: (212) 382-2124

E-mail: pto@steinbergraskin.com

FORM PTO-1449 (REV. 7-80) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.: 932.1308

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## LIST OF PRIOR ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT(S): Xavier VILANOVA et al.

FILING DATE: Herewith GROUP: Not yet known

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EXAMINER

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.